

Tetra-*n*-butylammonium hexafluorophosphateFrauke Schödel, Hans-Wolfram
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Key indicators

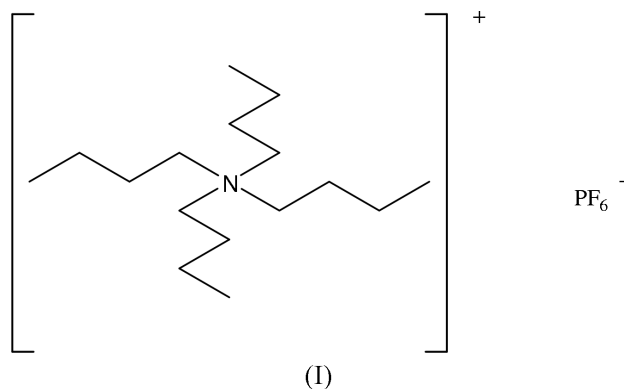
Single-crystal X-ray study
 $T = 173$ K
Mean $\sigma(\text{C}-\text{C}) = 0.005$ Å
 R factor = 0.057
 wR factor = 0.159
Data-to-parameter ratio = 15.6For details of how these key indicators were
automatically derived from the article, see
<http://journals.iucr.org/e>.

The structure of the title compound, $\text{C}_{16}\text{H}_{36}\text{N}^+\cdot\text{PF}_6^-$, has been reported previously by Angaridis, Cotton & Petrukhina [*Inorg. Chim. Acta* (2001), **324**, 318–323]. However, these authors found the PF_6^- ion to be heavily disordered and they did not publish any coordinates. We present here a redetermination of this structure, based on new intensity data and exhibiting no disorder.

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Comment

A perspective view of the title compound, (I), is shown in Fig. 1. The structure is composed of discrete $[\text{C}_{16}\text{H}_{36}\text{N}]^+$ cations and PF_6^- anions. Bond lengths and angles can be regarded as normal (Cambridge Structural Database, Version 1.6 plus three updates; *MOGUL* Version 1.0; Allen, 2002). Just one C–C–C torsion angle deviates from an anti-periplanar conformation [$\text{C41}-\text{C42}-\text{C43}-\text{C44} = 71.0$ (4)°]; the other three angles are close to 180°. Since no coordinates from the previously published structure determination of this compound (Angaridis *et al.*, 2001) are available, no comparison between the two structure determinations can be made.



Experimental

X-ray quality crystals of (I) were obtained on recrystallization from CH_2Cl_2 at ambient temperature.

Crystal data

$\text{C}_{16}\text{H}_{36}\text{N}^+\cdot\text{PF}_6^-$
 $M_r = 387.43$
Monoclinic, $P2_1/c$
 $a = 9.4057$ (19) Å
 $b = 13.593$ (2) Å
 $c = 14.982$ (3) Å
 $\beta = 91.367$ (16)°
 $V = 1914.9$ (6) Å³
 $Z = 4$

$D_x = 1.344$ Mg m⁻³
Mo $K\alpha$ radiation
Cell parameters from 7863
reflections
 $\theta = 2.6$ – 24.8 °
 $\mu = 0.20$ mm⁻¹
 $T = 173$ (2) K
Rod, colourless
 $0.29 \times 0.14 \times 0.12$ mm

Data collection

Stoe IPDS-II two-circle
diffractometer
 ω scans
Absorption correction: none
13397 measured reflections
3379 independent reflections

1764 reflections with $I > 2\sigma(I)$
 $R_{\text{int}} = 0.081$
 $\theta_{\text{max}} = 25.0^\circ$
 $h = -11 \rightarrow 11$
 $k = -16 \rightarrow 16$
 $l = -17 \rightarrow 16$

Refinement

Refinement on F^2
 $R[F^2 > 2\sigma(F^2)] = 0.057$
 $wR(F^2) = 0.159$
 $S = 0.91$
3379 reflections
217 parameters

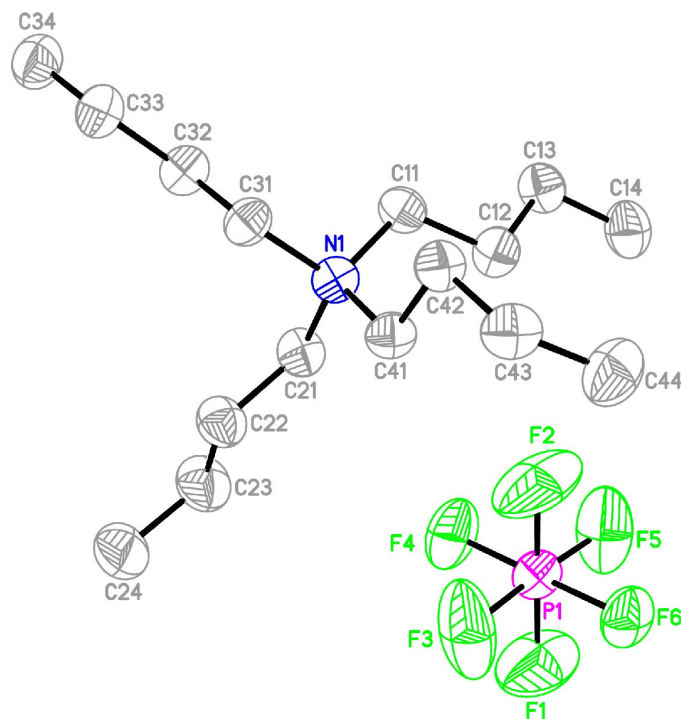
H-atom parameters constrained
 $w = 1/[\sigma^2(F_o^2) + (0.0896P)^2]$
where $P = (F_o^2 + 2F_c^2)/3$
 $(\Delta/\sigma)_{\text{max}} < 0.001$
 $\Delta\rho_{\text{max}} = 0.50 \text{ e } \text{\AA}^{-3}$
 $\Delta\rho_{\text{min}} = -0.49 \text{ e } \text{\AA}^{-3}$

H atoms were refined with fixed individual displacement parameters [$U_{\text{iso}}(\text{H}) = 1.2U_{\text{eq}}(\text{C})$ or $1.5U_{\text{eq}}(\text{C}_{\text{methyl}})$], using a riding model, with C—H = 0.99 and 0.98 Å for methylene and methyl H atoms, respectively.

Data collection: *X-AREA* (Stoe & Cie, 2001); cell refinement: *X-AREA*; data reduction: *X-AREA*; program(s) used to solve structure: *SHELXS97* (Sheldrick, 1990); program(s) used to refine structure: *SHELXL97* (Sheldrick, 1997); molecular graphics: *XP* in *SHELXTL-Plus* (Sheldrick, 1991); software used to prepare material for publication: *SHELXL97* and *PLATON* (Spek, 2003).

References

- Allen, F. H. (2002). *Acta Cryst.* **B58**, 380–388.
Angaridis, P., Cotton, F. A. & Petrukhina, M. A. (2001). *Inorg. Chim. Acta*, **324**, 318–323.
Sheldrick, G. M. (1990). *Acta Cryst.* **A46**, 467–473.
Sheldrick, G. M. (1991). *SHELXTL-Plus*. Release 4.1. Siemens Analytical X-ray Instruments Inc., Madison, Wisconsin, USA.

**Figure 1**

Perspective view of the title compound, with the atom numbering; displacement ellipsoids are drawn at the 50% probability level and H atoms have been omitted for clarity.

- Sheldrick, G. M. (1997). *SHELXL97*. University of Göttingen, Germany.
Spek, A. L. (2003). *J. Appl. Cryst.* **36**, 7–13.
Stoe & Cie (2001). *X-AREA*. Stoe & Cie GmbH, Darmstadt, Germany.